

July 2010

FDME1024NZT

Dual N-Channel PowerTrench MOSFET 20 V, 3.8 A, 66 m Ω

Features

- Max $r_{DS(on)}$ = 66 m Ω at V_{GS} = 4.5 V, I_D = 3.4 A
- Max $r_{DS(on)}$ = 86 m Ω at V_{GS} = 2.5 V, I_D = 2.9 A
- Max $r_{DS(on)}$ = 113 m Ω at V_{GS} = 1.8 V, I_D = 2.5 A
- Max $r_{DS(on)} = 160 \text{ m}\Omega$ at $V_{GS} = 1.5 \text{ V}$, $I_D = 2.1 \text{ A}$
- Low profile: 0.55 mm maximum in the new package MicroFET 1.6x1.6 **Thin**
- Free from halogenated compounds and antimony oxides
- HBM ESD protection level > 1600 V (Note 3)
- RoHS Compliant



General Description

This device is designed specifically as a single package solution for dual switching requirement in cellular handset and other ultra-portable applications. It features two independent N-Channel MOSFETs with low on-state resistance for minimum conduction losses.

The MicroFET 1.6x1.6 **Thin** package offers exceptional thermal performance for it's physical size and is well suited to switching and linear mode applications.

Applications

- Baseband Switch
- Load Switch



MicroFET 1.6x1.6 Thin

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V_{DS}	Drain to Source Voltage	Drain to Source Voltage			
V_{GS}	Gate to Source Voltage	±8	V		
	Drain Current -Continuous T _A = 25	°C (Note 1a)	3.8	۸	
I _D	-Pulsed		6	Α	
В	Power Dissipation for Single Operation $T_A = 25$	°C (Note 1a)	1.4	W	
P_{D}	Power Dissipation for Single Operation $T_A = 25$	°C (Note 1b)	0.6	7 VV	
T_J , T_{STG}	Operating and Storage Junction Temperature Rang	е	-55 to +150	°C	

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Single Operation)	(Note 1a)	90	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Single Operation)	(Note 1b)	195	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
4T	FDME1024NZT	MicroFET 1.6x1.6 Thin	7 "	8 mm	5000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	20			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		16		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 16 V, V _{GS} = 0 V			1	μА
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μА

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	0.4	0.7	1.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C		-3		mV/°C
	$V_{GS} = 4.5 \text{ V}, I_D = 3.4 \text{ A}$		55	66		
	r _{DS(on)} Static Drain to Source On Resistance	$V_{GS} = 2.5 \text{ V}, I_D = 2.9 \text{ A}$		68	86	
r _{DS(on)}		$V_{GS} = 1.8 \text{ V}, I_D = 2.5 \text{ A}$		85	113	mΩ
		$V_{GS} = 1.5 \text{ V}, I_D = 2.1 \text{ A}$		106	160	
		$V_{GS} = 4.5 \text{ V}, I_D = 3.4 \text{ A}, T_J = 125 \text{ °C}$		76	112	
9 _{FS}	Forward Transconductance	$V_{DD} = 4.5 \text{ V}, I_{D} = 3.4 \text{ A}$		9		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 40 V V 0 V	225	300	pF
C _{oss}	Output Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	40	55	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1/11/12	25	40	pF

Switching Characteristics

t _{d(on)}	Turn-On Delay Time			4.5	10	ns
t _r	Rise Time	V _{DD} = 10 V, I _D = 1 A,		2	10	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 4.5 \text{ V}, R_{GEN} = 6 \Omega$		15	27	ns
t _f	Fall Time			1.7	10	ns
Qg	Total Gate Charge	V 40.V/ L 0.4.A		3	4.2	nC
Q _{gs}	Gate to Source Gate Charge	Gate to Source Gate Charge $V_{DD} = 10 \text{ V}, I_D = 3.4 \text{ A}, V_{GS} = 4.5 \text{ V}$		0.4		nC
Q_{gd}	Gate to Drain "Miller" Charge	VGS = 4.5 V		0.6		nC

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 V, I_{S} = 0.9 A$ (Note 2)		0.7	1.2	V
t _{rr}	Reverse Recovery Time	I _E = 3.4 A, di/dt = 100 A/μs		8.5	17	ns
Q _{rr}	Reverse Recovery Charge	1 _F = 3.4 A, di/dt = 100 A/μs		1.4	10	nC

^{1.} R_{0JA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.



a. 90 °C/W when mounted on a 1 in² pad of 2 oz copper.



b. 195 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300 $\mu\text{s},$ Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection ESD. No gate overvoltage rating is implied.

Typical Characteristics T_J = 25 °C unless otherwise noted

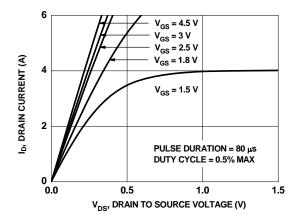


Figure 1. On-Region Characteristics

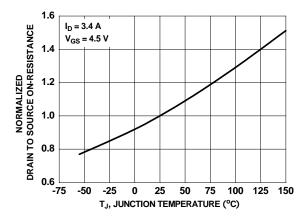


Figure 3. Normalized On-Resistance vs Junction Temperature

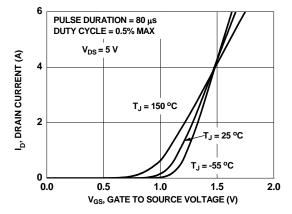


Figure 5. Transfer Characteristics

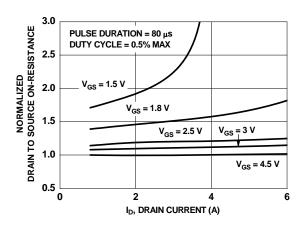


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

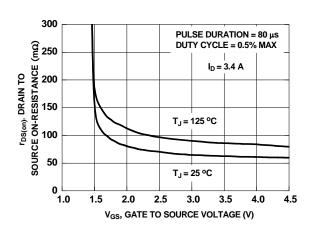


Figure 4. On-Resistance vs Gate to Source Voltage

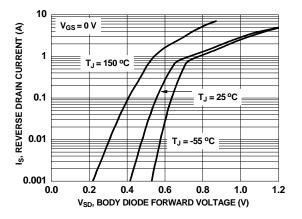


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25$ °C unless otherwise noted

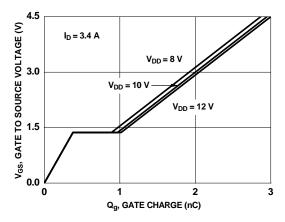


Figure 7. Gate Charge Characteristics

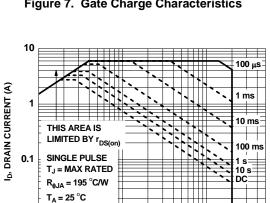


Figure 9. Forward Bias Safe Operating Area

V_{DS}, DRAIN to SOURCE VOLTAGE (V)

10

50

0.01 L 0.1

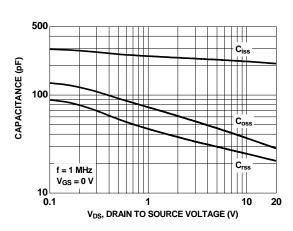


Figure 8. Capacitance vs Drain to Source Voltage

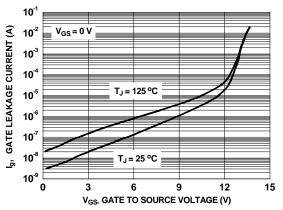


Figure 10. Gate Leakage Current vs **Gate to Source Voltage**

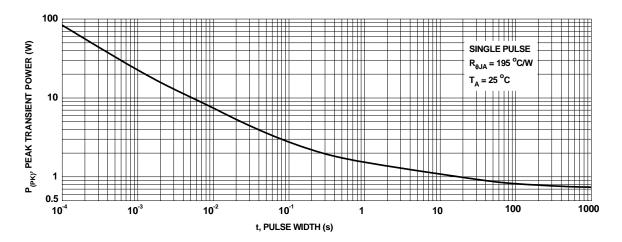


Figure 11. Single Pulse Maximum Power Dissipation

Typical Characteristics $T_J = 25$ °C unless otherwise noted

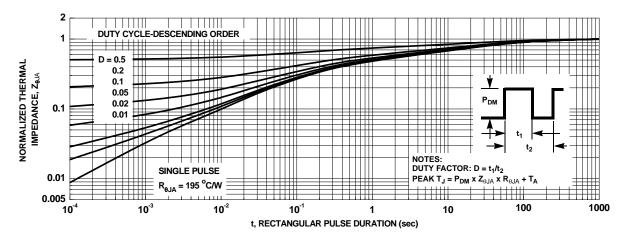
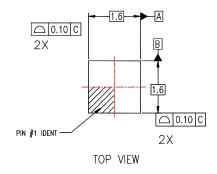
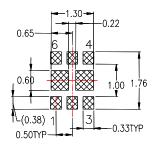


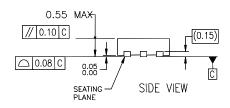
Figure 12. Junction-to-Ambient Transient Thermal Response Curve

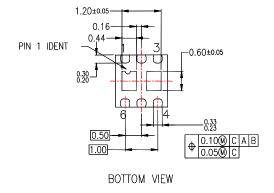
Dimensional Outline and Pad Layout





RECOMMENDED LAND PATTERN









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